

CUSTOMER 客户.

规格书编号

**SPEC NO:** 

# 产品规格书 SPECIFICATION

PRODUCT 产品:	SAW RESONATOR		
MODEL NO 型 号:	HDR293.125M SMD-20		
PREPARED 编 制:	CHECKED 审 核	ξ <b>:</b>	
APPROVED 批准:	<b>DATE</b> 日 期	2006-5-11	
客户确认 CUSTOMER RE	ECEIVED:		
审核 CHECKED	批准 APPROVED	日期 DATE	

## 无锡市好达电子有限公司 Shoulder Electronics Limited

## 更改历史记录 History Record

更改日期 Date	规格书编号 Spec. No.	产品型号 Part No.	客户产品型号 Customer No.	更改内容描述 Modify Content	备注 Remark



### 1. SCOPE

This specification shall cover the characteristics of 1-port SAW resonator with 293.125M used for remote-control security.

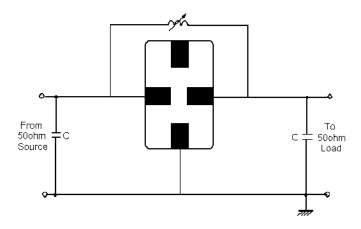
#### 2. ELECTRICAL SPECIFICATION

DC Voltage VDC	10V	
AC Voltage Vpp	10V50Hz/60Hz	
Operation temperature	-40°C to +85°C	
Storage temperature	-45°C to +85°C	
RF Power Dissipation	0dBm	

#### 2.2 Electronic Characteristics

Item		Unites	Minimum	Typical	Maximum
Center Frequency		MHz	292.050	293.125	293.200
Insertion Loss		dB		1.5	2.5
Quality Factor Unload Q			8000	12800	
50Ω Loaded	Q		1000	2000	
Temperature	Turnover Temperature	°C	10	25	40
Stability	Freq.temp.Coefficient	ppm/°C2		0.032	
Frequency Aging		ppm/yr		<±10	
DC. Insulation Resistance		$\mathbf{M} \Omega$	1.0		
Motional Resistance R1		Ω		16	26
RF Equivalen	Motional Inductance L1	μН		138.46	
KLC Wlodel	Motional Capacitance C1	fF		2.1292	
Pin 1 to Pin 2 Staic Capacitance		pF	1.5	2.0	2.5
Transducer Static Capacitance		pF		2.6	

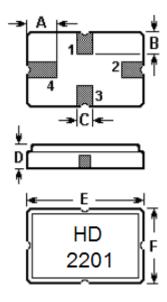
#### 3. TEST CIRCUIT





#### 4. DIMENSION

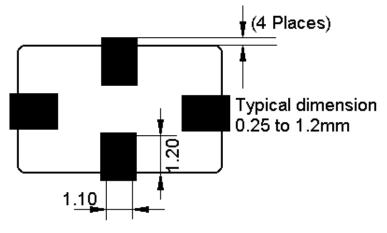
#### 4-1 Typical dimension(unit: mm)



Pin	Configuration	
1	Input / Output	
3	Output / Input	
2/4	Case Ground	

Sign	Data (unit: mm)	Sign	Data (unit: mm)
Α	1.2±0.1	D	1.4±0.1
В	0.8±0.1	Е	5.0±0.1
С	0.5	F	3.5±0.1

#### 4-2 Typical circuit board land patter



#### **SAW RESONATOR**

#### 5. ENVIRONMENTAL CHARACTERISTICS

#### 5-1 High temperature exposure

Subject the device to  $+85^{\circ}$ C for 16 hours. Then release the resonator into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in 2.2.

#### 5-2 Low temperature exposure

Subject the device to  $-40^{\circ}$ C for 16 hours. Then release the device into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in 2.2.

#### 5-3 Temperature cycling

Subject the device to a low temperature of  $-40^{\circ}$ C for 30 minutes. Following by a high temperature of  $+85^{\circ}$ C for 30 Minutes. Then release the device into the room conditions for 24 hours prior to the measurement. It shall meet the specifications in 2.2.

#### 5-4 Resistance to solder heat

Dip the device terminals no closer than 1.5mm into the solder bath at  $260^{\circ}$ C  $\pm 10^{\circ}$ C for  $10\pm 1$  sec. Then release the device into the room conditions for 4 hours. The device shall meet the specifications in 2.2.

#### 5-5 Solderability

Subject the device terminals into the solder bath at  $245^{\circ}$ C  $\pm 5^{\circ}$ C for 5s, More than 95% area of the terminals must be covered with new solder. It shall meet the specifications in 2.2.

#### 5-6 Mechanical shock

Drop the device randomly onto the concrete floor from the height of 1m 3 times. the device shall fulfill the specifications in 2.2.

#### 5-7 Vibration

Subject the device to the vibration for 1 hour each in x,y and z axes with the amplitude of 1.5 mm at 10 to 55 Hz. The device shall fulfill the specifications in 2.2.

#### 6. REMARK

#### 6.1 Static voltage

Static voltage between signal load & ground may cause deterioration &destruction of the component. Please avoid static voltage.

#### 6.2 Ultrasonic cleaning

Ultrasonic vibration may cause deterioration & destruction of the component. Please avoid ultrasonic cleaning

#### 6.3 Soldering

Only leads of component may be soldered. Please avoid soldering another part of component.